

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3047	382/141,144-145,147,149,151.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:35
L2	748	348/85,86,125,126.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:35
L3	313	702/58.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:35
L4	3844	1 2 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:36
L5	2486239	wafer semiconductor (semi adj conductor) mask photomask (photo adj mask) ic (integrat\$3 adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:37
L6	41165	5 near (inspect\$ detect\$ defect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:38
L7	6891	(signature reference ideal master golden template) near pixel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:39
L8	48	6 same 7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:39
L9	3	(signature near pixel) and wafer and defect and (individual near pixel).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:41

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L10	3	(signature near pixel) and wafer and defect and (individual near pixel).clm.	US-PGPUB	OR	ON	2005/09/15 12:41

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